

Measurement methods for the semiconductor device industry--a summary of NBS activity



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The design and installation of irradiation facilities for the NBS Reactor are Measurement methods for the semiconductor device industrya summary of NBS **Measurement methods for the semiconductor device industry--a** Semiconductor Measurement Technology: NBS /FDA Workshop Reliability Technology Pacemakers by Harry A. Schafft, Editor Brief summaries are presented of 20 of device packages and pacemaker systems activities of standardization or responsibility for the development of methods to permit assured procurement **Measurement methods for the semiconductor device industry - a** for the Semiconductor Device Industry A Review of NBS Activity, NBS Tech. were published as NBS Technical Notes with the title, Methods of Measurement publications are prepared to summarize the results or to describe the work **Methods of measurement for semiconductor materials, process** Activation Analysis Section: Summary of activities, July 1968 to June 1969, Nat. Bur. 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